

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

HIRANO ET AL.

Examiner

OMONIYI A. OBAYANJU

Art Unit

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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0126692	09-2002	Haartsen, Jacobus	370/450
*	B US-2003/0214928	11-2003	Chuah, Mooi Choo	370/336
*	C US-7,154,877	12-2006	Le et al.	370/346
*	D US-7,280,518	10-2007	Montano et al.	370/338
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
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T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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V	
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